

Ion beam microscopy in serve of material investigations

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High-energy ion microscopes attached to an ion accelerator system are highly versatile research instruments for applications in high-resolution material investigations capable of precise tuning for a given sample or task. Their design and flexibility is usually closely related to properties of the accelerator system. We used a suite of ion nanobeams (proton, alpha, carbon and oxygen ions) with magnetic rigidity (ME/q2) value up to 40 MeV amu/e2 provided by the high-energy ion microscope of accelerator facility at ANSTO for here presented material investigation studies of micron-sized sample structures or micron-sized particles from very different origins. Examples include bio systems, health, electronics, manufacturing and cultural heritage.

Keywords: material, structure, microscopy, ion nanobeam

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Level of Expertise

Expert

Do yo wish to take part in the poster slam

Travel Funding

No

Speakers Gender

Male

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